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ILNAS-EN IEC 61000-4-6:2023

Electromagnetic compatibility (EMC) - Part 4-6: Testing and measurement techniques - Immunity to conducted disturbances, induced by radio-

Elektromagnetische Verträglichkeit (EMV)
- Teil 4-6: Prüf- und Messverfahren -
Störfestigkeit gegen leitungsgeführte
Störgrößen, induziert durch

Compatibilité électromagnétique (CEM) -
Partie 4-6: Techniques d'essai et de
mesure - Immunité aux perturbations
conduites, induites par les champs aux

07/2023



National Foreword

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**Electromagnetic compatibility (EMC) - Part 4-6: Testing and measurement techniques - Immunity to conducted disturbances, induced by radio-frequency fields
(IEC 61000-4-6:2023)**

Compatibilité électromagnétique (CEM) - Partie 4-6:
Techniques d'essai et de mesure - Immunité aux perturbations conduites, induites par les champs aux fréquences radioélectriques
(IEC 61000-4-6:2023)

Elektromagnetische Verträglichkeit (EMV) - Teil 4-6: Prüf- und Messverfahren - Störfestigkeit gegen leitungsgeführte Störgrößen, induziert durch hochfrequente Felder
(IEC 61000-4-6:2023)

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European Committee for Electrotechnical Standardization
Comité Européen de Normalisation Electrotechnique
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European foreword

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The following dates are fixed:

- latest date by which the document has to be implemented at national (dop) 2024-04-11 level by publication of an identical national standard or by endorsement
- latest date by which the national standards conflicting with the (dow) 2026-07-11 document have to be withdrawn

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In the official version, for Bibliography, the following notes have to be added for the standard indicated:

IEC 61000-4-3 NOTE Approved as EN IEC 61000-4-3

CISPR 16-1-4 NOTE Approved as EN IEC 55016-1-4

Annex ZA (normative)

Normative references to international publications with their corresponding European publications

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

NOTE 1 Where an International Publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

NOTE 2 Up-to-date information on the latest versions of the European Standards listed in this annex is available here: www.cenelec.eu.

<u>Publication</u>	<u>Year</u>	<u>Title</u>	<u>EN/HD</u>	<u>Year</u>
CISPR 16-1-2	-	Specification for radio disturbance and immunity measuring apparatus and methods - Part 1-2: Radio disturbance and immunity measuring apparatus - Coupling devices for conducted disturbance measurements	EN 55016-1-2	-



INTERNATIONAL STANDARD



BASIC EMC PUBLICATION

**Electromagnetic compatibility (EMC) –
Part 4-6: Testing and measurement techniques – Immunity to conducted
disturbances, induced by radio-frequency fields**

CONTENTS

FOREWORD.....	6
INTRODUCTION.....	8
1 Scope.....	9
2 Normative references	9
3 Terms and definitions	9
4 General	11
5 Test levels.....	13
6 Test equipment and level adjustment procedure	15
6.1 Test generator	15
6.2 Coupling and decoupling devices.....	16
6.2.1 General	16
6.2.2 Coupling/decoupling networks (CDNs).....	18
6.2.3 Clamp injection devices	20
6.2.4 Direct injection devices.....	22
6.2.5 Decoupling networks	22
6.3 Verification of the common-mode impedance at the EUT port of coupling and decoupling devices	22
6.3.1 General	22
6.3.2 Insertion loss of the 150 Ω to 50 Ω adapters	23
6.4 Setting of the test generator.....	25
6.4.1 General	25
6.4.2 Setting of the output level at the EUT port of the coupling device	25
7 Test setup and injection methods	27
7.1 Test setup.....	27
7.2 EUT comprising a single unit.....	28
7.3 EUT comprising several units.....	30
7.4 Rules for selecting injection methods and test points	31
7.4.1 General	31
7.4.2 Injection method	31
7.4.3 Ports to be tested	32
7.5 CDN injection application	32
7.6 Clamp injection application	34
7.7 Direct injection application	36
8 Test procedure	36
9 Evaluation of the test results	37
10 Test report.....	38
Annex A (normative) EM and decoupling clamps.....	39
A.1 EM clamps	39
A.1.1 General	39
A.1.2 Specification of EM clamps.....	39
A.2 EM clamp characterization	41
A.2.1 Specification of the clamp test jig	41
A.2.2 Clamp characterization	42
A.3 Decoupling clamp characterization.....	47
A.3.1 General	47
A.3.2 Specification of decoupling clamps	47

A.3.3	Impedance.....	47
A.3.4	Decoupling factor.....	48
Annex B (informative)	Selection criteria for the frequency range of application	50
Annex C (informative)	Guidelines for selecting test levels	52
Annex D (informative)	Information on coupling and decoupling networks	53
D.1	Basic features of the coupling and decoupling networks.....	53
D.2	Examples of coupling and decoupling networks	53
Annex E (informative)	Information for the test generator specification	58
Annex F (informative)	Test setup for large EUTs.....	59
F.1	General.....	59
F.2	Test setup for large EUTs	59
Annex G (informative)	Measurement uncertainty of the voltage test level.....	62
G.1	General.....	62
G.2	General symbols	62
G.3	Uncertainty budgets for test methods	62
G.3.1	Definition of the measurand	62
G.3.2	MU contributors of the measurand	63
G.3.3	Input quantities and calculation examples for expanded uncertainty	64
G.4	Expression of the calculated measurement uncertainty and its application	71
Annex H (informative)	Testing with multiple signals	73
H.1	General.....	73
H.2	Intermodulation	73
H.3	Power requirements	74
H.4	Level-setting requirements	75
H.5	Linearity check and harmonics checks of the test generator.....	75
H.6	EUT performance criteria with multiple signals.....	75
Annex I (informative)	Port-to-port injection	76
I.1	General.....	76
I.2	Test setup for injection on identical ports	76
I.2.1	Selection of ports.....	76
I.2.2	Procedure for port-to-port injection	76
Annex J (informative)	Amplifier compression and non-linearity.....	78
J.1	Objective of limiting amplifier distortion	78
J.2	Possible problems caused by harmonics and saturation.....	78
J.3	Limiting the harmonic content in the disturbance signal.....	78
J.4	Effect of linearity characteristic on the immunity test.....	79
J.4.1	General	79
J.4.2	Evaluation of the amplifier linearity characteristic	79
Bibliography	83
Figure 1 – Diagram showing EM fields near the EUT due to common-mode currents on its cables		12
Figure 2 – Schematic setup for immunity test to RF conducted disturbances.....		13
Figure 3 – Example of unmodulated and modulated RF signal		14
Figure 4 – Test generator setup		16
Figure 5 – Principle of coupling and decoupling – Symbols used for the indicated setup principles		17

Figure 6 – Principle of coupling and decoupling – Principle of direct injection to screened cables.....	17
Figure 7 – Principle of coupling and decoupling – Principle of coupling to unscreened cables according to the CDN method	18
Figure 8 – Principle of coupling and decoupling – Principle of decoupling	18
Figure 9 – Example of circuit for evaluating the transmission loss of the current clamp level-setting	21
Figure 10 – Example of circuit for level-setting setup in a 150 Ω test jig	21
Figure 11 – Example of the setup geometry to verify the impedance characteristics of the coupling and decoupling devices.....	23
Figure 12 – Setup principle to verify Z_{ce} of the coupling and decoupling device.....	24
Figure 13 – Setup principle for measuring the insertion loss of two 150 Ω to 50 Ω adapters	24
Figure 14 – Circuit and construction of the 150 Ω to 50 Ω adapter	24
Figure 15 – Definition of a common-mode point for unscreened and screened cables	26
Figure 16 – Setup for level-setting at the EUT port of the coupling/decoupling devices	27
Figure 17 – Example of test setup with a single unit EUT with only one CDN for injection (top view).....	28
Figure 18 – Example of test setup with a single unit EUT (top view) using multiple CDNs.....	29
Figure 19 – Example of a test setup with a multi-unit EUT (top view)	30
Figure 20 – Rules for selecting the injection method	31
Figure 21 – Immunity test for two-port EUT (when only one CDN can be used).....	34
Figure 22 – General principle of a test setup using clamp injection devices	35
Figure 23 – Example of the test unit locations on the ground plane when using injection clamps (top view).....	36
Figure A.1 – Example: Construction details of the EM clamp.....	40
Figure A.2 – Example: Concept of the EM clamp	41
Figure A.3 – Dimension of a reference plane	42
Figure A.4 – Test jig	42
Figure A.5 – Test jig with inserted clamp.....	42
Figure A.6 – Impedance / decoupling factor measurement setup	43
Figure A.7 – Typical examples for clamp impedance, three typical clamps.....	45
Figure A.8 – Typical examples for decoupling factors, three typical clamps.....	45
Figure A.9 – Normalization setup for coupling factor measurement	46
Figure A.10 – S_{21} coupling factor measurement setup	46
Figure A.11 – Typical examples for coupling factor, three typical clamps	47
Figure A.12 – Decoupling clamp characterization measurement setup.....	48
Figure A.13 – Typical examples for the decoupling clamp impedance	48
Figure A.14 – Typical examples for decoupling factors.....	49
Figure B.1 – Start frequency as function of cable length and equipment size	51
Figure D.1 – Example of a simplified diagram for the circuit of CDN-S1 used with screened cables (see 6.2.2.5).....	54
Figure D.2 – Example of simplified diagram for the circuit of CDN-M1, CDN-M2 and CDN-M3 used with unscreened supply (mains) lines (see 6.2.2.2)	54

Figure D.3 – Example of a simplified diagram for the circuit of CDN-AF2 used with unscreened unbalanced lines (see 6.2.2.4)	55
Figure D.4 – Example of a simplified diagram for the circuit of CDN-T2, used with an unscreened balanced pair (see 6.2.2.3)	55
Figure D.5 – Example of a simplified diagram of the circuit of CDN-T4 used with unscreened balanced pairs (see 6.2.2.3)	56
Figure D.6 – Example of a simplified diagram of the circuit of CDN AF8 used with unscreened unbalanced lines (see 6.2.2.4)	56
Figure D.7 – Example of a simplified diagram of the circuit of CDN-T8 used with unscreened balanced pairs (see 6.2.2.3)	57
Figure F.1 – Example of large EUT test setup with elevated horizontal reference ground plane.....	60
Figure F.2 – Example of large EUT test setup with vertical reference ground plane	61
Figure G.1 – Example of influences upon voltage test level using CDN	63
Figure G.2 – Example of influences upon voltage test level using EM clamp	63
Figure G.3 – Example of influences upon voltage test level using current clamp	63
Figure G.4 – Example of influences upon voltage test level using direct injection.....	64
Figure G.5 – Circuit for level-setting setup of CDN.....	65
Figure H.1 – Test frequencies f_1 and f_2 and intermodulation frequencies of the second and third order	73
Figure I.1 – Example of setup, port-to-port injection	77
Figure J.1 – Amplifier linearity measurement setup	80
Figure J.2 – Linearity characteristic	81
Figure J.3 – Measurement setup for modulation depth	81
Figure J.4 – Spectrum of AM modulated signal	82
Table 1 – Test levels.....	14
Table 2 – Characteristics of the test generator.....	15
Table 3 – Main parameter of the combination of the coupling and decoupling device	16
Table 4 – Usage of CDNs	19
Table B.1 – Main parameter of the combination of the coupling and decoupling device when the frequency range of the test is extended above 80 MHz	50
Table E.1 – Required power amplifier output power to obtain a test level of 10 V	58
Table G.1 – CDN level-setting process	65
Table G.2 – CDN test process	65
Table G.3 – EM clamp level-setting process	67
Table G.4 – EM clamp test process.....	68
Table G.5 – Current clamp level-setting process	69
Table G.6 – Current clamp test process	69
Table G.7 – Direct injection level-setting process.....	70
Table G.8 – Direct injection test process.....	71